

Lecture 3: Semiconductors for Photovoltaics

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Semiconductors



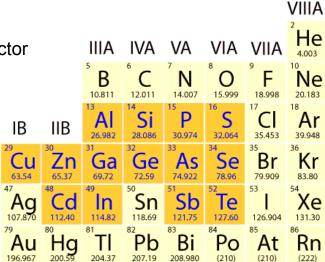
Semiconductor materials typically from either group IV of the periodic table, or combination of III-V or II-VI

As semiconductors made from different elements the properties vary

Silicon (group IV)

- most commonly used semiconductor material as it forms the basis for integrated circuit (IC) industry
- most mature technology
- most solar cells are Si based

∴ Si will be used as a model material over next few lectures



Source: http://www.pveducation.org/pvcdrom/pn-junction/semiconductor-materials

Silicon



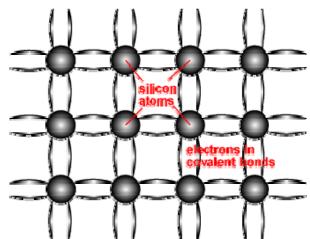
Silicon – individual atoms bonded together in a periodic structure so that each atom is surrounded by 8 electrons.

Si atom – nucleus contains a core of protons (positively charged particles) and neutrons (particles having no charge) surrounded by electrons.

Number of electrons (e^-) = protons so as atom is overall electrically neutral

Electrons form a covalent bond – two atoms sharing a single *e*[–](eight overall between four covalent bonds)

Bond structure determines the material properties of a semiconductor



Source: http://www.pveducation.org/pvcdrom/pn-junction/semiconductor-structure

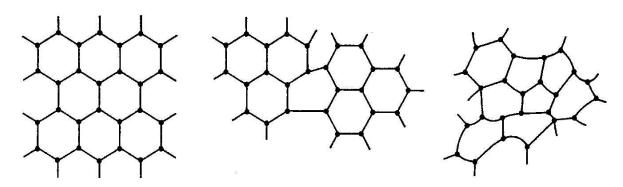
Silicon

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Silicon – depending on fabrication technique can get different material structure that affect properties greatly:

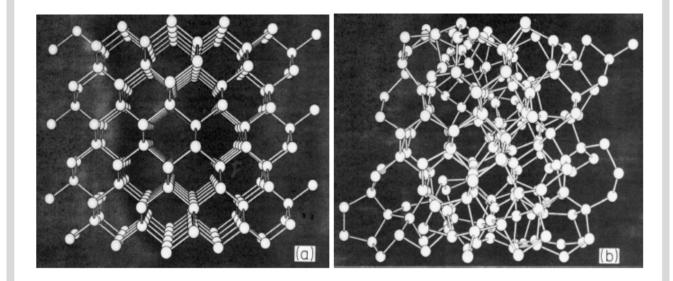
- Single crystal (c-Si): atoms are periodically arranged in a lattice
- Poly- or multi-crystalline (mc-Si): there are regions of crystallinity but no long range order
- Amorphous silicon (a-Si): only short range order exists and no periodicity



Source: Wolfe, Holonyak, Stillman

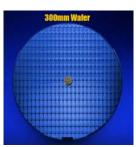
Silicon





Silicon

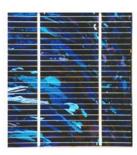
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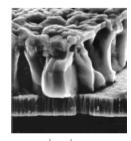
300 mm wafer for Si microelectronics



Monocrystalline Si solar cell

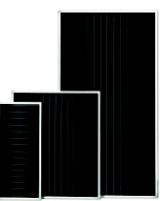


Multicrystalline Si solar cell



Electron microscope image of thin film solar cell





ASI®-F 2-10/12

PV modules made from amorphous silicon



Effect: which *E* levels e⁻ can occupy and how they move within crystal

Bonded *e*⁻ typically regarded as being bound, i.e. are not considered "free" to participate in current flow, absorption, or other physical processes of interest in solar cells.

Only strictly true at absolute zero – at elevated T (at which solar cells operate) e^- can gain enough energy to escape the bond. Thus, is no longer in its low energy state but is now "free" in a high energy state

Two distinct energy states for e^- (no intermediate level possible) \Rightarrow minimum energy called the semiconductor "bandgap"

Empty space left behind by e^- allows covalent bond to move, appearing to be positive charge moving through the crystal lattice – commonly called a "hole", h^+ (similar to e^- but with positive charge)

Source: http://www.pveducation.org/pvcdrom/pn-junction/semiconductor-structure

Conduction in Semiconductors



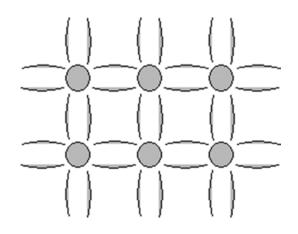
Most important parameters of a semiconductor for solar cell operation are:

• the band gap;

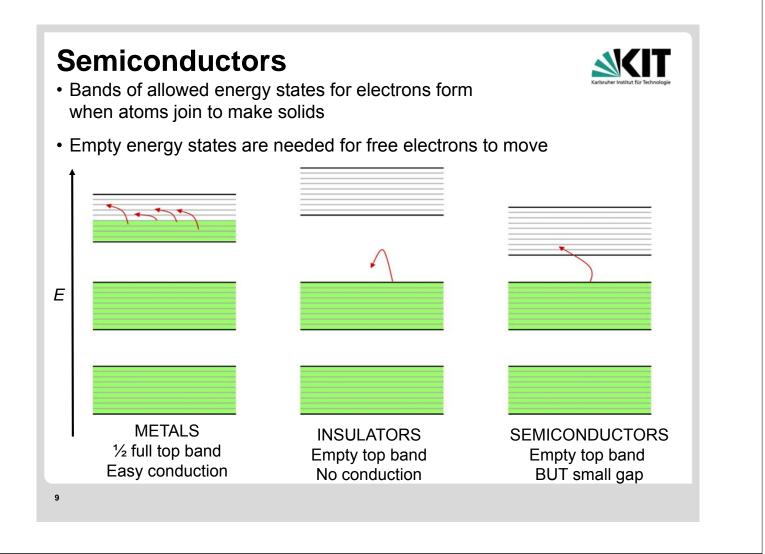
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- the number of free carriers (electrons or holes) available for conduction;
- the "generation" and recombination of free carriers (electrons or holes) in response to light shining on the material.

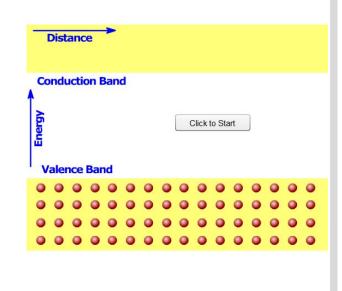


Source: http://www.pveducation.org/pvcdrom/pn-junction/conduction-in-semiconductors





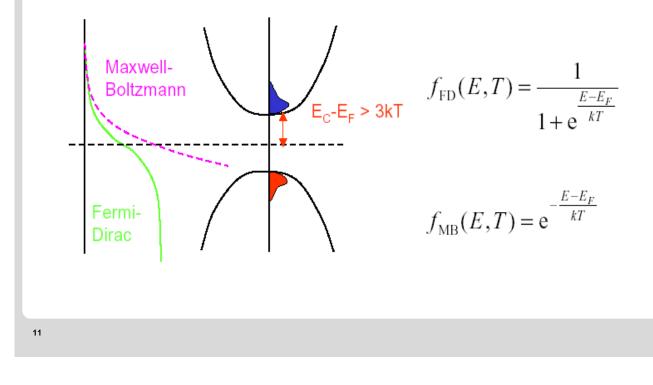
- Lower energy level called the "valence band" (E_{ν})
- "Conduction band" (E_c) energy level at e^- is considered free
- Band gap (E_q) energy between these bound and free states



Source: http://www.pveducation.org/pvcdrom/pn-junction/band-gap



- We also define the Fermi level as $E_d/2$
- Occupation of *E_c* and *E_v* follows Fermi-Dirac distribution and the Maxwell-Boltzmann approximation:



Conduction in Semiconductors



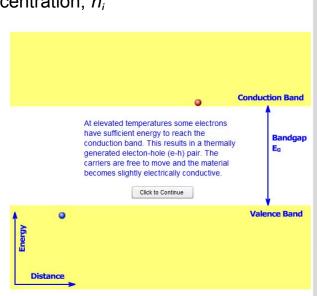
Semiconductor material with no added impurities to change the carrier concentrations is called <u>intrinsic</u> material. Concentration of the carriers (e^- and h^+) is called the intrinsic carrier concentration, n_i

 $n_i \propto E_g$ and T

Intuitively:

- large *E_g* makes it harder and ∴ *n_i* is lower in wide *E_g* materials
- Increasing *T* makes it more likely that *e*⁻ will be excited into *E_c*, which increases *n_i*

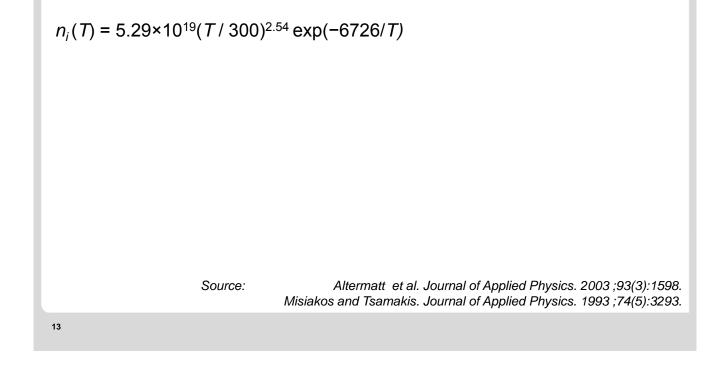
Impacts directly on solar cell efficiency



Source: http://www.pveducation.org/pvcdrom/pn-junction/intrinsic-carrier-concentration



At 300 K, the exact value of n_i in silicon is generally accepted to be 9.65 x 10⁹ cm⁻³ (Altermatt *et al.*) and a general formula for n_i in Si as function of *T* is given by (Misiakos and Tsamakis):



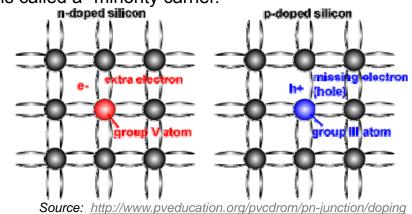
Conduction in Semiconductors



Change balance of e^- and h^+ in Si crystal lattice by <u>doping</u> with other atoms

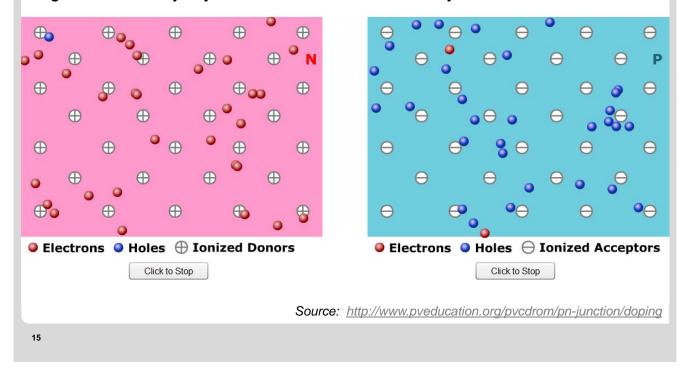
- group V elements have one more valence e⁻ than Si and produce "n-type" semiconductor material
- group III elements have one less valence e⁻ than Si and produce "p-type" semiconductor material

In doped material, there is always more of one type of carrier than the other. Carrier with the higher concentration is called a "majority carrier", while the lower concentration carrier is called a "minority carrier."





n-type Si (majority carriers are <u>N</u>egatively charged electrons) *p*-type Si (majority carriers are <u>P</u>ositively charged holes) e.g. 10^{17} cm⁻³ majority carriers and 10^{6} cm⁻³ minority carriers



Conduction in Semiconductors



No. carriers in E_c and E_v with no external bias = equilibrium carrier concentration

For majority carriers, this is equal to the n_i plus the number of free carriers added by doping. Usually semiconductor doping is >> n_i such that the number of majority carriers is approximately equal to the doping.

At equilibrium, the product of majority and minority carrier concentration is a constant - Law of Mass Action:

$$n_0 p_0 = n_i^2$$

where n_0 and p_0 are the electron and hole equilibrium carrier concentrations



Thus, the majority and minority carrier concentrations are:

n-type:
$$n_0 = N_D$$
, $p_0 = \frac{n_i^2}{N_D}$
p-type: $p_0 = N_A$, $n_0 = \frac{n_i^2}{N_A}$
where N_D and N_A are
the concentration of
donor and acceptor
atoms, respectively.
Source: http://www.pveducation.org/pvcdrom/pn-junction/equilibrium-carrier-concentration

Absorption of Light



Photons incident on semiconductor will be either:

- i. reflected from the top surface,
- ii. absorbed in the material or,
- iii. transmitted through the material.

For PV devices, i) and iii) reflection and transmission are losses \Rightarrow photons which are not absorbed do not generate power

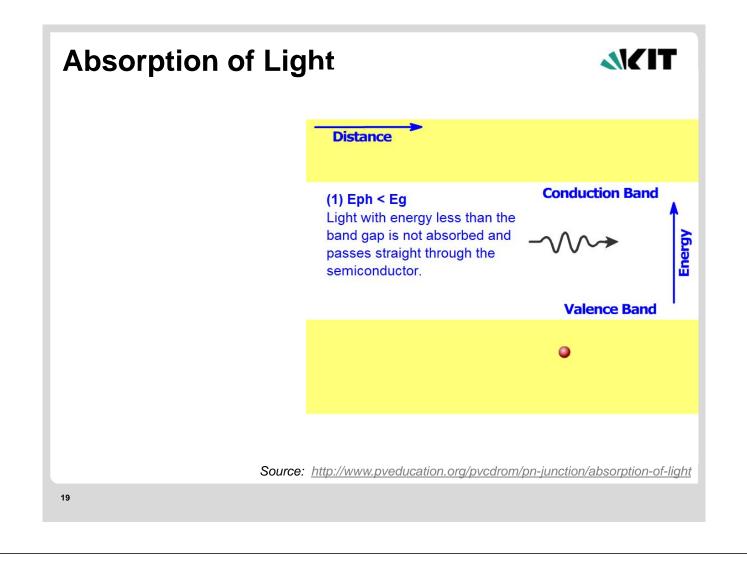
If photon is absorbed, possibility of exciting an e^- from E_v to E_c but depends on energy of photon, E_{ph} :

 $E_{ph} < E_g$: pass through semiconductor as if it were transparent

 $E_{ph} = E_g$: enough energy to create an $e^{-}-h^+$ pair and are efficiently absorbed

 $E_{ph} > E_g$: strongly absorbed, but the excess photon energy is wasted as carriers quickly thermalize back down to the band edges

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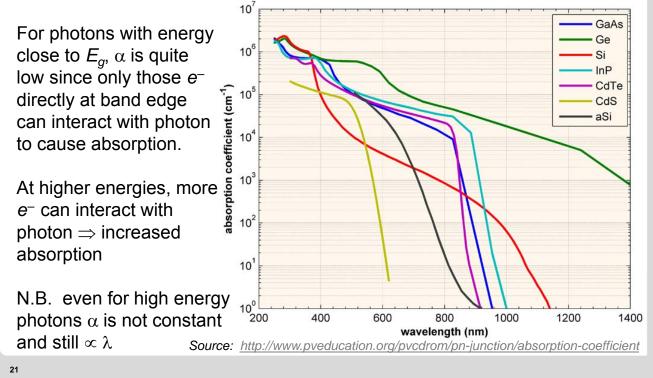
Absorption of photons creates both a majority and a minority carrier

Typically, the number of light-generated carriers are << number of majority carriers already present in the solar cell due to doping

Thus, number of majority carriers in an illuminated semiconductor does not alter significantly, but number of photo-generated minority carriers >> number of minority carriers existing in the doped solar cell in the dark



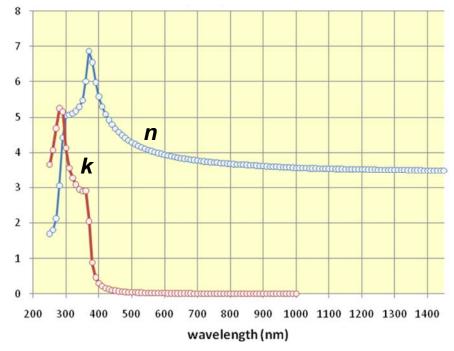
Absorption coefficient (α) determines how far into a material light of a particular wavelength can penetrate before it is absorbed.



Absorption of Light



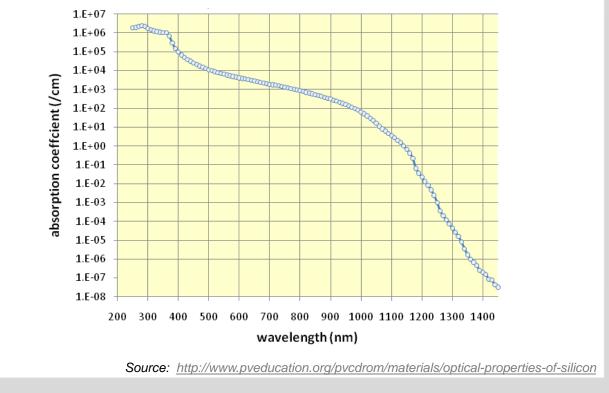
Refractive index (n) and extinction coefficient (k) of silicon



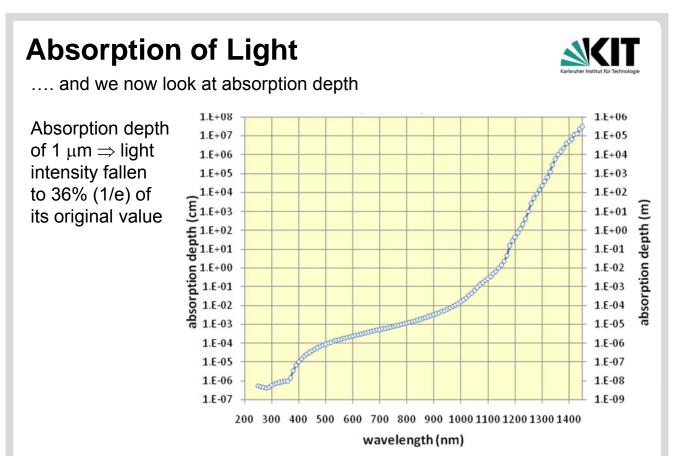
Source: http://www.pveducation.org/pvcdrom/materials/optical-properties-of-silicon



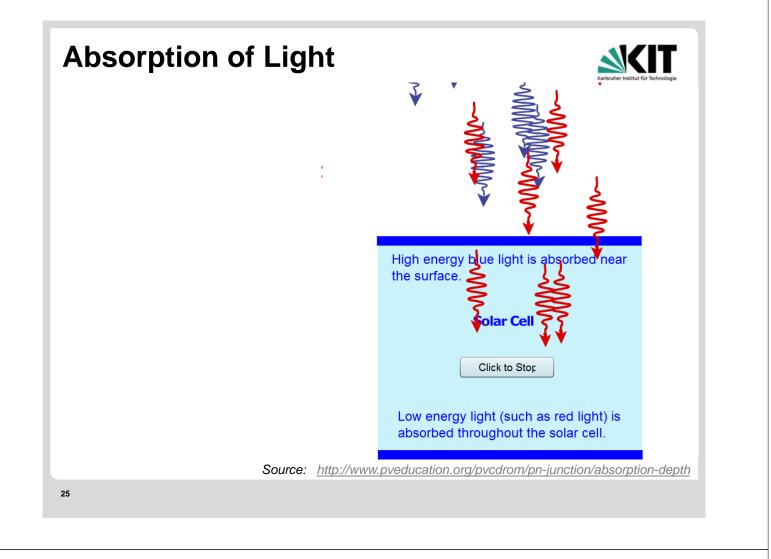
Revisiting the absorption coefficient plot....



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Source: http://www.pveducation.org/pvcdrom/materials/optical-properties-of-silicon



Absorption of Light For two other common semiconductors: gallium arsenide (GaAs) and germanium (Ge) 100 GaAs Absorption Depth Ge Absorption Depth 10 Absorption Depth (µm) Absorption Depth (µm) 1 0.1 0.1 0.01 0.01 0.001 L 200 0.001 L 200 800 300 400 500 600 700 400 600 800 1000 1200 1400 160(Wavelength (nm) Wavelength (nm)

Source: http://www.pveducation.org/pvcdrom/pn-junction/absorption-depth



The generation rate = no. e^- generated at each point in the device due to the absorption of photons

Neglecting reflection, amount of light absorbed α and the thickness of the absorber. Intensity of light can be calculated according to:

 $I = I_0 e^{-\alpha x}$

where:

 α is absorption coefficient (cm⁻¹); x is the distance into the material; and I_0 is the light intensity at the top surface.

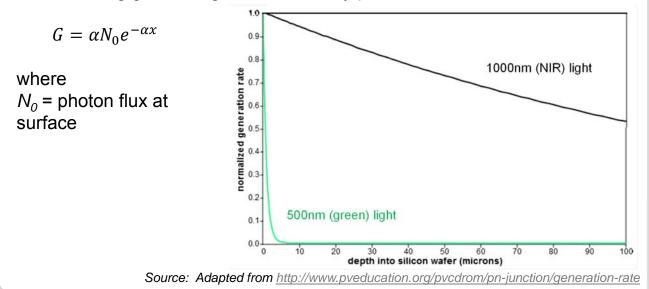


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Absorption of Light



Same equation can be used to calculate the number of $e^{-}h^+$ pairs being generated in a solar cell. Assuming that the loss in light intensity is due to the absorption of photons and the generation of an $e^{-}h^+$ pair, generation *G* is determined by finding the change in light intensity across this slice. Thus, differentiating gives the generation at any point in the device:



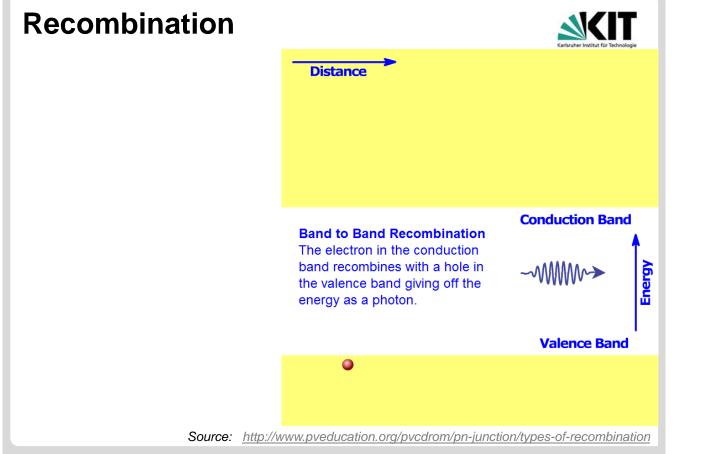


Any e^- in E_c is in meta-stable state and will eventually stabilize to a lower energy position in E_v

For this to happen, it must move into an empty valence band state. Thus, when e^- stabilizes back down into E_v it effectively removes a $h^+ \Rightarrow$ process called recombination.

There are three basic types of recombination in the bulk of a single-crystal semiconductor. These are:

- Radiative recombination
- Auger recombination
- Shockley-Read-Hall recombination





<u>Radiative (Band-to-Band) Recombination</u> dominates in direct bandgap semiconductors. The light produced from a LED is most obvious example of radiative recombination in a semiconductor device.

While some concentrator and space solar cells are made from direct bandgap materials (e.g. GaAs) and radiative recombination dominates. However, most terrestrial solar cells are made from Si, which is an indirect bandgap semiconductor and radiative recombination is extremely low

Recombination



Recombination Through Defect Levels, also called <u>Shockley-Read-Hall</u> (SRH) recombination only occurs in material with defects.

SRH recombination is a two-step process.

- *i*) e⁻ (or *h*⁺) is trapped by an energy state in the forbidden region, introduced through defects in the crystal lattice. Defects can be either unintentionally introduced or deliberately added to material, e.g. doping
- ii) if h^+ (or e^-) moves up to the same energy state before the e^- is thermally re-emitted into E_c , then it recombines

Rate at which a carrier moves into the energy level in the forbidden gap depends on the distance of the introduced energy level from either of the band edges. If an energy level is introduced close to either band edge, recombination is less likely as the e^- is likely to be re-emitted to E_c edge rather than recombine with a h^+ which moves into the same energy state from E_v . For this reason, energy levels near mid-gap are very effective for recombination.



<u>Auger Recombination</u> involves three carriers. An e^- and h^+ recombine, but rather than emitting the energy as heat or as a photon, the energy is given to a third carrier, an e^- electron in E_c . This e^- then thermalizes back down to edge of E_c . edge.

Auger recombination is most important at high carrier concentrations caused by heavy doping or high level injection under concentrated sunlight. In Si solar cells, Auger recombination limits the lifetime and ultimate efficiency.

Recombination



If the no. of minority carriers is increased above the equilibrium value by some transient external excitation (e.g. sunlight), excess minority carriers will decay back to that equilibrium carrier concentration due via a process of recombination.

⇒ critical solar cell parameter is the "recombination rate", which links to minority carrier lifetime and the minority carrier diffusion length



Minority carrier lifetime, denoted by τ_n or τ_p , is average time which a carrier can spend in an excited state after e^{-} - h^+ generation before recombining

Often just called "lifetime" but has nothing to do with material stability

The low level injected material (where the number of minority carriers is less than the doping) the lifetime is related to the recombination rate by:

$$\tau = \frac{\Delta n}{R}$$

where Δn is the excess minority carriers concentration and R is the recombination rate

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Recombination



And

$$\frac{1}{\tau_{bulk}} = \frac{1}{\tau_{band}} + \frac{1}{\tau_{Auger}} + \frac{1}{\tau_{SRH}}$$

And the Auger lifetime is a function of the carrier concentration, given by:

$$\tau_{Auger} = \frac{1}{C{N_A}^2}$$

where the auger coefficient, C, for Si is typically 1.66×10^{-30} cm⁶/s



Second parameter related to recombination rate, is "minority carrier diffusion length" = average distance a carrier can move from point of generation until it recombines

In Si, τ can be ≥ 1 ms. \Rightarrow for single crystal silicon solar cell, the diffusion length is typically 100 – 300 µm (gives indication of material quality).

The diffusion length *L* is related to τ by the diffusivity according to:

 $L = \sqrt{D\tau}$

where L is the diffusion length in meters and D is the diffusivity in m^2/s

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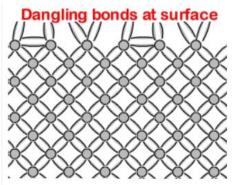
Recombination



Surface recombination is high as large amounts of defects exist where the crystal lattice is disrupted. Understanding the impacts and the ways to limit surface recombination leads to better and more robust solar cell designs.

The high recombination rate in the vicinity of a surface depletes this region of minority carriers. A localized region of low carrier concentration causes carriers to flow into this region from the surrounding, higher concentration regions. Therefore, the surface recombination

rate is limited by the rate at which minority carriers move towards the surface. A parameter called the "surface recombination velocity" (units of cm/s) is used to specify the recombination at a surface. In a surface with infinitely fast recombination, the movement of carriers towards this surface is limited by the maximum velocity they can attain, and for most semiconductors is on the order of 1 x 10⁷ cm/sec



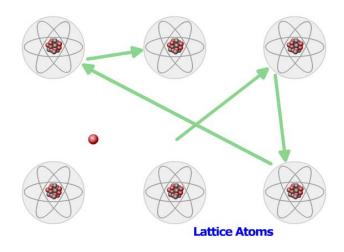
Source: http://www.pveducation.org/pvcdrom/pn-junction/surface-recombination



 e^- in E_c and h^+ in E_v are "free" carriers – can move throughout the semiconductor lattice

Simple but adequate description of carrier movement views each carrier as moving in a random direction at a certain velocity.

Carrier moves in random direction for a distance called scattering length before colliding with a lattice atom. After collision, carrier then moves away in a different random direction.



Source: http://www.pveducation.org/pvcdrom/pn-junction/movement-of-carriers-in-semiconductors

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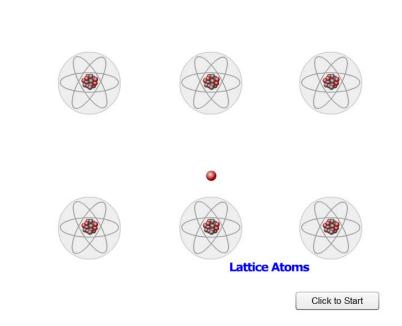
Movement of Carriers in Semicond.



 e^- in E_c and h^+ in E_v are "free" carriers – move through Si crystal.

Carrier moves in random direction for a distance called scattering length before colliding with a lattice atom. After collision, carrier then moves away in a different random direction.

The velocity of the carriers is determined by the temperature of the lattice



Source: http://www.pveducation.org/pvcdrom/pn-junction/movement-of-carriers-in-semiconductors



Although carriers in a semiconductor are in constant random motion, there is <u>no net</u> <u>motion of carriers</u> – unless there is a concentration gradient or an electric field

Click to Stop

Source: http://www.pveducation.org/pvcdrom/pn-junction/movement-of-carriers-in-semiconductors

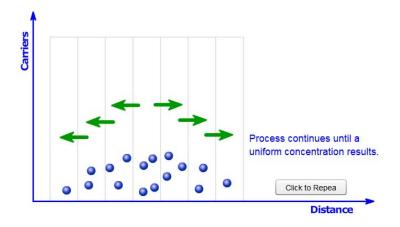
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Movement of Carriers in Semicond.



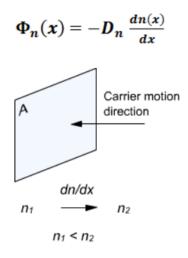
Diffusion - random motion of carriers can lead to a net movement of carriers if one particular region has a higher concentration than another (i.e. concentration gradient) \Rightarrow net movement of carriers from areas of high concentration to low.

Rate of diffusion depends on velocity at which carriers move and on the distance between scattering events – termed diffusivity and measured in cm²s⁻¹





Flux of diffusing particles is ∞ to concentration gradient For ELECTRONS: For HOLES:



$$\Phi_p(x) = -D_p \, \frac{dp(x)}{dx}$$

where Φ_n is the electron flux, D_n is the electron diffusion coefficient (units cm²/s), and n_1 and n_2 are the electron concentrations. Minus sign arises from the fact that the vector of the concentration gradient is directed toward the increase of the concentration (particles diffuse from n_1 to n_2)

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Movement of Carriers in Semicond.



Diffusion current density = carrier flux density \times carrier charge (denoted by *q*)

$$J_{n_diff} = qD_n \frac{dn}{dx} \qquad \qquad J_{p_diff} = -qD_p \frac{dp}{dx}$$

where the elementary charge, $q = 1.602 \times 10^{-19}$ coulombs

Diffusion and drift (next slide) properties are fundamentally related via the Einstein relations:

$$D_n = rac{kT}{q} \mu_n$$
 and $D_p = rac{kT}{q} \mu_p$

where μ_n and μ_p are carrier mobilities for electrons and holes, respectively (units: cm²V⁻¹s⁻¹)

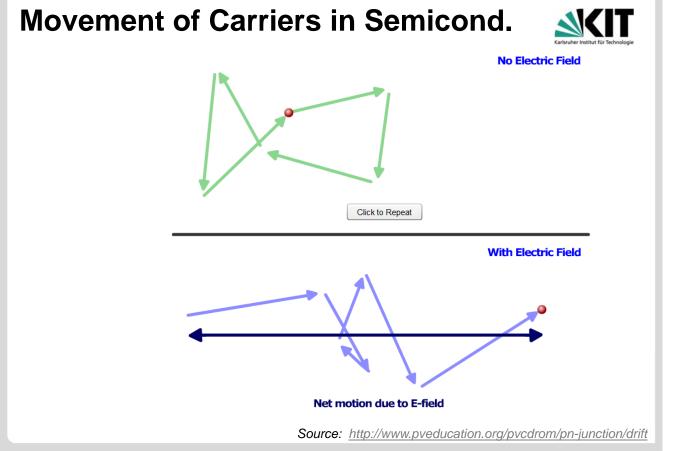


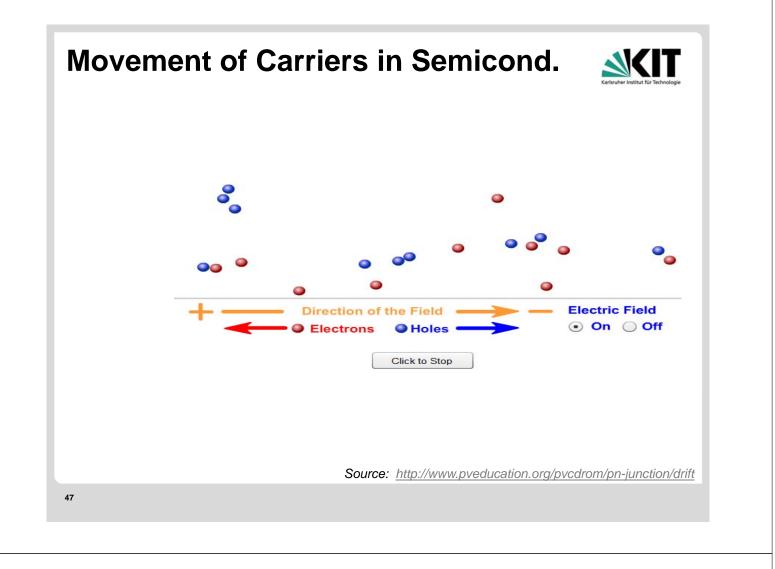
Earlier, we noted that in the absence of an electric field, carriers move a certain distance at a constant velocity in a random direction.

Now, with an electric field superimposed on this random direction, carriers move in a net direction. There is an acceleration in direction of the electric field if the carrier is h^+ , or opposite to the electric field if the carrier is e^-

Net carrier movement in the presence of an electric field is characterized by mobility (varies between different semiconductor materials)

Transport due to the movement of carriers due to the presence of an electric field is called "drift transport", e.g. same type of transport that also occurs in metals







One-dimensional current density flow due to drift is given by:

$$J_{n_drift} = q \ n \ \mu_n \ E_x$$

 $J_{p_drift} = q \ p \ \mu_p \ E_x$

where:

 J_x is the current density in the *x*-direction, E_x (or ξ) - electric field applied in the x-direction, q - electron charge, n and p - electron and hole concentrations, μ_n and μ_p - electron and hole mobilities

Total current flow is the sum, hence conductivity σ can be defined as:

$$\sigma = \frac{1}{\rho} = \frac{J}{\xi_n} = q n \mu_n + q p \mu_p$$

where ρ is the resistivity (typical unit: Ω .cm)

Poisson's equation relates the divergence of electric field to the space charge density, ρ :

 $\frac{d\xi}{dx} = \frac{\rho}{\epsilon}$ where ϵ = permittivity

Contributions to charge density in semiconductor:

- e^- in E_c contribute negative charge, whereas h^+ give positive charge
- donor impurity that is ionised, i.e. had extra electron removed, has a net positive charge due to unneutralised positive charge at nucleus (N_D^+) and vice versa for an ionised acceptor (N_A^-)

Hence

$$\rho = q(p - n + N_D^+ - N_A^-)$$

N.B. most donors and acceptors are ionised under normal conditions so that $N_D^+ \approx N_D$ and $N_A^- \approx N_A$

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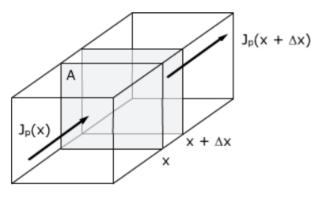
Movement of Carriers in Semicond.



Overall total current densities for e^- and h^+ are the sum of the drift and diffusion processes:

$$J_n = q \ n \ \mu_n \ E_x + q D_n \frac{dn}{dx} \qquad \qquad J_p = q \ p \ \mu_p \ E_x - q D_p \frac{dp}{dx}$$

Final "book-keeping" equations to keep track of no. of e^- and h^+ in system, e.g. consider a volume of cross-sectional area A and of length Δx





Net rate of increase of e^- = rate at which e^- enter – rate at which e^- exit + rate at which they are generated – rate at which they recombine

Rates of entering and exiting ∞ current densities, hence:

Rate of entering – rate exiting
$$= \frac{A}{q} \{-J_n(x) - [-J_n(x + \Delta x)]\}$$

 $= \frac{A}{q} \frac{dJ_n}{dx} \Delta x$

Rate of generation – rate of recombination = $\frac{A}{q} \Delta x (G - U)$

where G is net generation rate by external processes (e.g. light) and U is the recombination rate. Under steady-state conditions the net rate of increase must be zero such that:

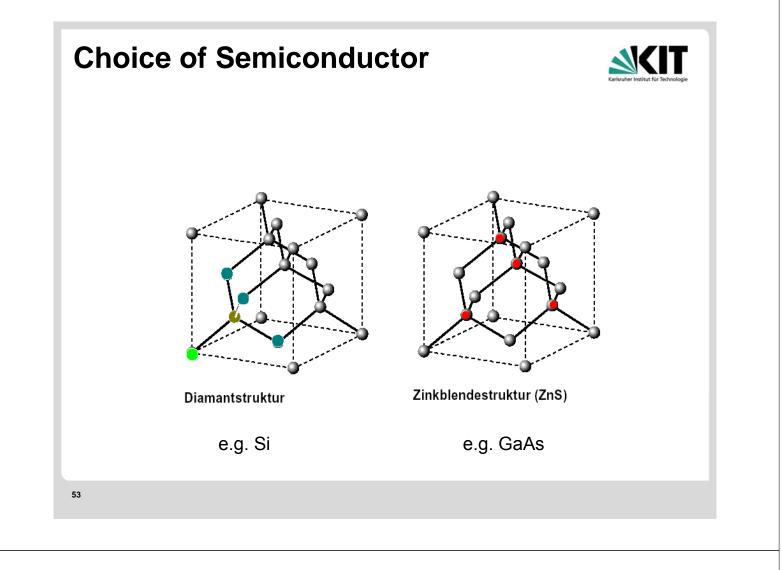
 $\frac{1}{q} \frac{dJ_n}{dx} \Delta x = U - G$ and $\frac{1}{q} \frac{dJ_p}{dx} \Delta x = -(U - G)$

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Choice of Semiconductor



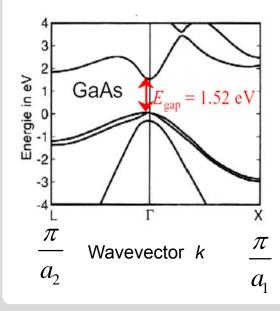
- Maximise absorption of sunlight ideal solar cell is black!
- Efficiency of converting absorbed energy into electrical energy
- Avoid to many energy conversion processes (e.g. thermal losses)
- Cost
- Environmentally-friendly?
- Stability (under UV, water vapour, etc)



Choice of Semiconductor



· GaAs is a direct bandgap semiconductor

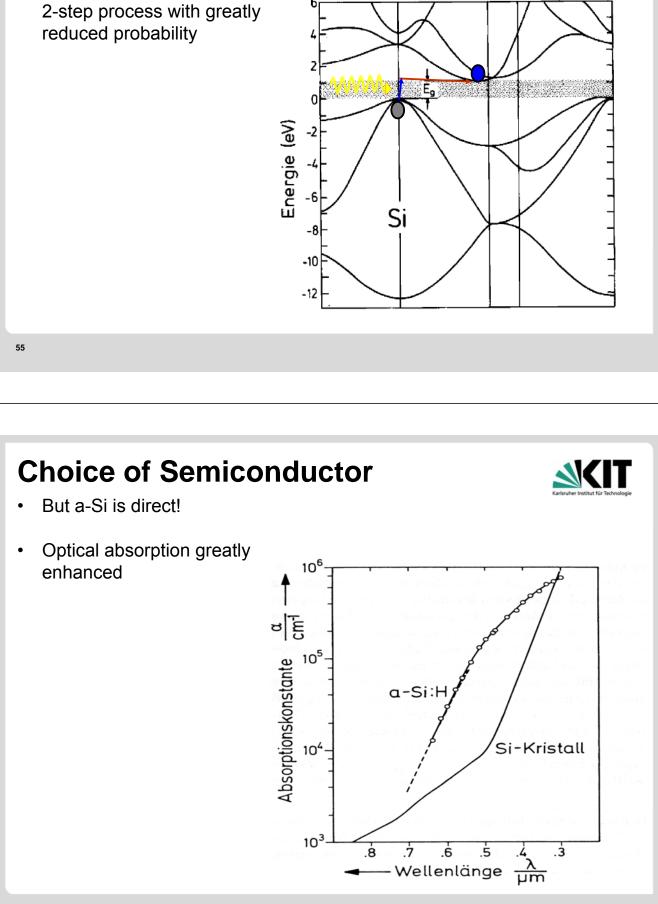


Choice of Semiconductor



Whereas c-Si is an indirect semiconductor

Optical absorption is a



Choice of Semiconductor



Overall, there is a compromise between:

- Absorption of widest possible spectral range (narrow bandgap)
- And the losses due to relaxation at the band edges (wide bandgap)
- \Rightarrow trade-off!

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